Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/909,176	FUCCELLO ET AL.
Examiner	Art Unit

Tri H. Phan

2661

SEARCHED					
Class	Subclass	Date	Examiner		
370	310,315, 328,338, 400-401	8/8/2005	TP		
370	395.2+	8/8/2005	TP		
370	395.52	8/8/2005	TP		
709	217-219	8/8/2005	TP		
709	223-229	8/8/2005	TP		
709	249	8/8/2005			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEARC		')
	DATE	EXMR
EAST, IEEE, Internet search	8/8/2005	TP
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